

November 2009
Ultra FRFET

FDP5N50U / FDPF5N50UT N-Channel MOSFET, FRFET 500V, 4A, 2.0 Ω

Features

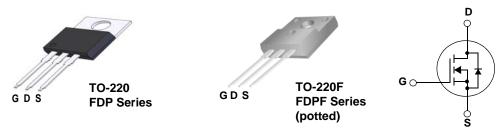
- $R_{DS(on)} = 1.65\Omega$ (Typ.)@ $V_{GS} = 10V$, $I_D = 2A$
- Low gate charge (Typ. 11nC)
- Low C_{rss} (Typ. 5pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS compliant



Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DOMS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutationmode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter		FDP5N50U	FDPF5N50UT	Units
V_{DSS}	Drain to Source Voltage			5	V	
V_{GSS}	Gate to Source Voltage			±30		V
ı	Drain Current	-Continuous (T _C = 25°C)		4	4*	Α
ID	Diam Current	-Continuous (T _C = 100°C)		2.4	2.4*	A
I _{DM}	Drain Current	- Pulsed	(Note 1)	16	16*	Α
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	216		mJ
I _{AR}	Avalanche Current		(Note 1)	4		Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)	8.5		mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	4.5		V/ns
П	Dower Discipation	(T _C = 25°C)		85	28	W
P_{D}	Power Dissipation	- Derate above 25°C		0.67	0.22	W/oC
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to	+150	οС
T _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			3	00	°C

^{*}Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter F		FDPF5N50UT	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.4	4.5	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP5N50U	FDP5N50U	TO-220	-	-	50
FDPF5N50UT	FDPF5N50UT	TO-220F	-	-	50

Electrical Characteristics

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ} C$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.7	-	V/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 500V, V_{GS} = 0V$	-	-	25	
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 400V, T_C = 125^{\circ}C$	-	-	250	μА
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$		3	-	5	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 2A$		-	1.65	2	Ω
g _{FS}	Forward Transconductance	$V_{DS} = 40V, I_D = 2A$ (N	ote 4)	-	4.8	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 05)/ V 0)/		=	485	650	pF
C _{oss}	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz		-	65	90	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1101112		-	5	8	pF
Q _{g(tot)}	Total Gate Charge at 10V			-	11	15	nC
Q _{gs}	Gate to Source Gate Charge	$V_{DS} = 400V, I_{D} = 4A$		-	3	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V	(Note 4, 5)	-	5	-	nC

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			-	14	38	ns
t _r	Turn-On Rise Time	$V_{DD} = 250V, I_D = 4A$		-	21	52	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25\Omega$		-	27	64	ns
t _f	Turn-Off Fall Time		(Note 4, 5)	-	20	50	ns

Drain-Source Diode Characteristics

Is	Maximum Continuous Drain to Source Diode Forward Current			-	4	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	16	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 4A	-	-	1.6	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _{SD} = 4A	-	36	-	ns
Q _{rr}	Reverse Recovery Charge	$V_{GS} = 0V$, $I_{SD} = 4A$ $dI_F/dt = 100A/\mu s$ (Note 4)	-	33	-	nC

- Notes: Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature 2: L = 27mH, $I_{AS} = 4A$, $V_{DD} = 50V$, $R_{C} = 25\Omega$, Starting $T_{J} = 25^{\circ}C$ 3: $I_{SD} \le 4A$, di/dt $\le 200A/\mu$ s, $V_{DD} \le BV_{DSS}$, Starting $T_{J} = 25^{\circ}C$ 4: Pulse Test: Pulse width $\le 300\mu$ s, Duty Cycle $\le 2\%$ 5: Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

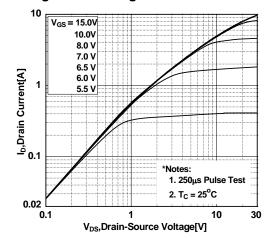


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

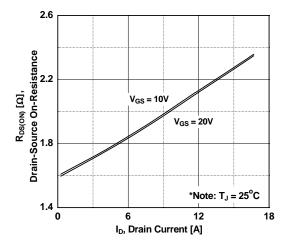


Figure 5. Capacitance Characteristics

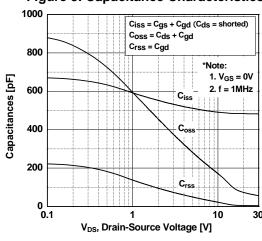


Figure 2. Transfer Characteristics

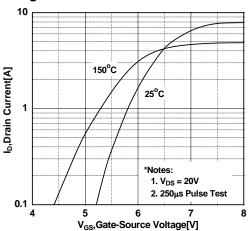


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

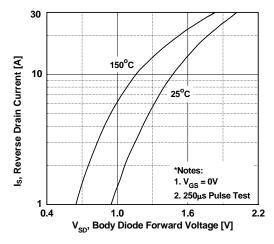
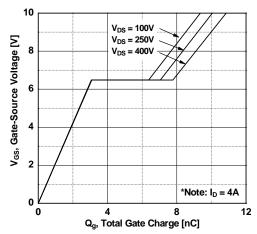


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

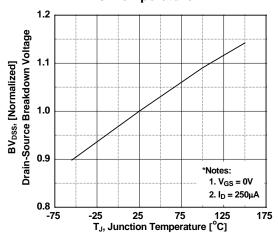


Figure 9. Maximum Safe Operating Area - FDPF5N50UT

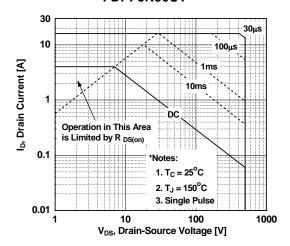


Figure 8. Maximum Safe Operating Area - FDP5N50U

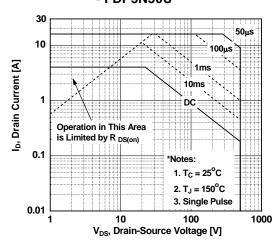


Figure 10. Maximum Drain Current vs. Case Temperature

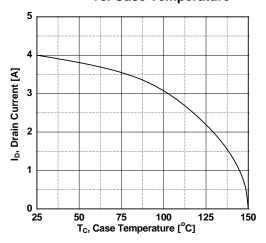
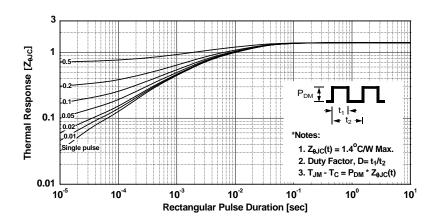
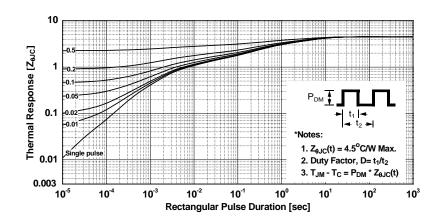


Figure 11. Transient Thermal Response Curve - FDP5N50U

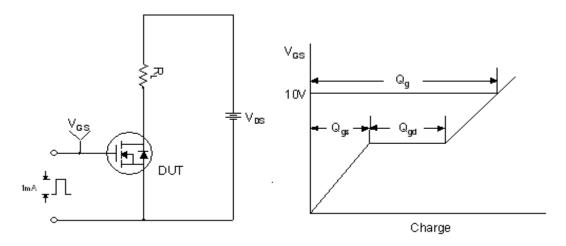


Typical Performance Characteristics (Continued)

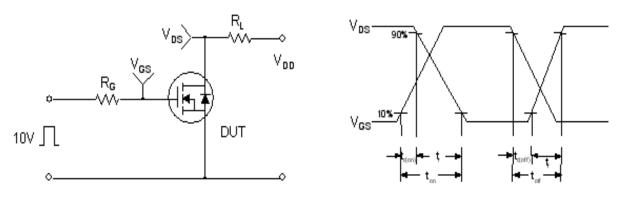
Figure 12. Transient Thermal Response Curve - FDPF5N50UT



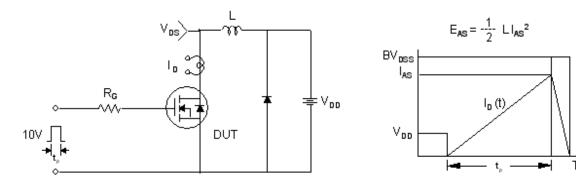
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

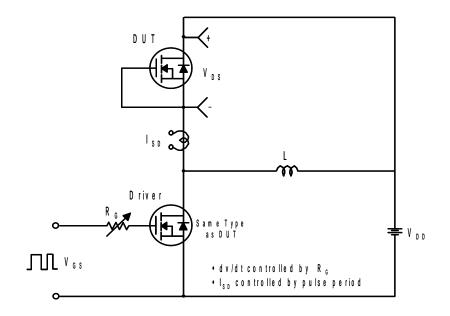


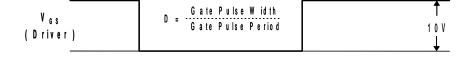
Unclamped Inductive Switching Test Circuit & Waveforms

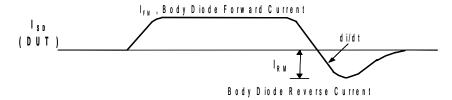


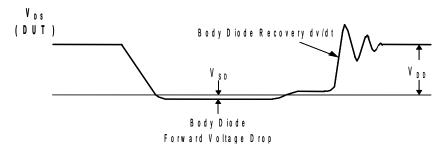
V_{os} (t)

Peak Diode Recovery dv/dt Test Circuit & Waveforms



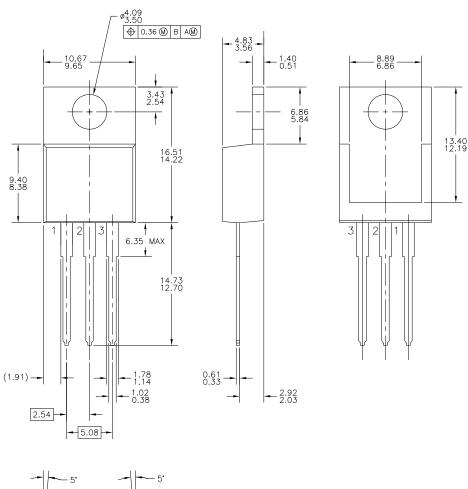






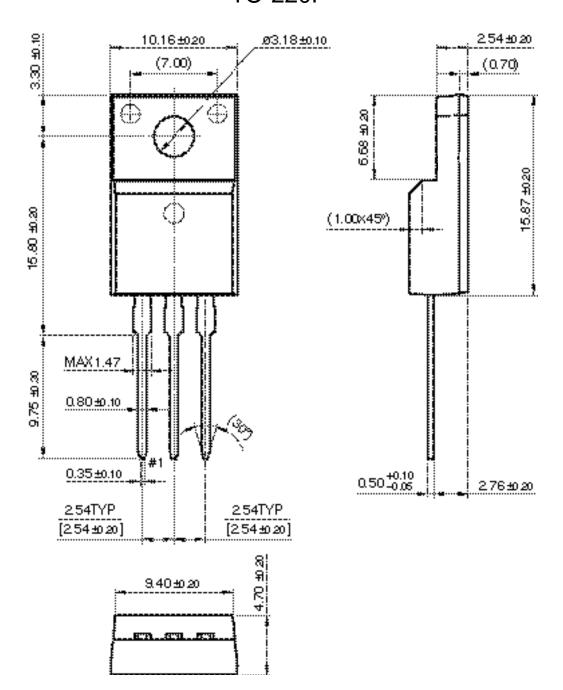
Mechanical Dimensions

TO-220



Package Dimensions (Continued)

TO-220F



* Front/Back Side Isolation Voltage: 2500V

Dimensions in Millimeters





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